CLAIMS

1. An electrical contact for use in an integrated circuit testing apparatus, comprising:

a rigid bottom member (10) having two planar surfaces (12, 14), said bottom member formed of an electrically conductive material;

a flexible top member (20) having two arms (22, 24) extending over said bottom member (10), said two arms having an inwards bias such that an inner surface (23, 25) of each said arm is pressed in contact with each said planar surface (12, 14), said top member formed of an electrically conductive material; and

a compressible member (30) located between a top end (16) of said bottom member (10) and a bifurcation inner surface (26) of said top member (20).

2. An electrical contact for use in an integrated circuit testing apparatus according to claim 1, wherein the said compressible member (30) has a cylindrical shape, and the said top end (16) of said bottom member (10) is adapted to match and receive the said compressible member (30).

3. An electrical contact for use in an integrated circuit testing apparatus according to claim 2, wherein the said bifurcation inner surface (26) of said top member (20) is adapted to match and receive the said compressible member (30).

4. An electrical contact for use in an integrated circuit testing apparatus according to claim 1, wherein the said two planar surfaces (12, 14) slope towards each other.

5. An electrical contact for use in an integrated circuit testing apparatus according to claim 4, wherein the angle of said slope of each planar surface (12, 14) to the vertical is between 0° and 20°.

6. An electrical contact for use in an integrated circuit testing apparatus according to claim 5, wherein the angle of said slope of each planar surface (12, 14) to the vertical is between 13° and 17°.